18.657: Mathematics of Machine Learning

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1. WHAT IS MACHINE LEARNING (IN THIS COURSE)?

This course focuses on *statistical learning theory*, which roughly means understanding the amount of data required to achieve a certain prediction accuracy. To better understand what this means, we first focus on stating some differences between *statistics* and *machine learning* since the two fields share common goals.

Indeed, both seem to try to use data to improve decisions. While these fields have evolved in the same direction and currently share a lot of aspects, they were at the beginning quite different. Statistics was around much before machine learning and statistics was already a fully developed scientific discipline by 1920, most notably thanks to the contributions of R. Fisher, who popularized maximum likelihood estimation (MLE) as a systematic tool for statistical inference. However, MLE requires essentially knowing the probability distribution from which the data is draw, up to some unknown parameter of interest. Often, the unknown parameter has a physical meaning and its estimation is key in better understanding some phenomena. Enabling MLE thus requires knowing a lot about the data generating process: this is known as modeling. Modeling can be driven by physics or prior knowledge of the problem. In any case, it requires quite a bit of domain knowledge.

More recently (examples go back to the 1960's) new types of datasets (demographics, social, medical,...) have become available. However, modeling the data that they contain is much more hazardous since we do not understand very well the input/output process thus requiring a *distribution free* approach. A typical example is image classification where the goal is to label an image simply from a digitalization of this image. Understanding what makes an image a cat or a dog for example is a very complicated process. However, for the classification task, one does not need to understand the labelling process but rather to replicate it. In that sense, machine learning favors a blackbox approach (see Figure 1).



Figure 1: The machine learning blackbox (left) where the goal is to replicate input/output pairs from past observations, versus the statistical approach that opens the blackbox and models the relationship.

These differences between statistics and machine learning have receded over the last couple of decades. Indeed, on the one hand, statistics is more and more concerned with finite sample analysis, model misspecification and computational considerations. On the other hand, probabilistic modeling is now inherent to machine learning. At the intersection of the two fields, lies *statistical learning theory*, a field which is primarily concerned with sample complexity questions, some of which will be the focus of this class.

2. STATISTICAL LEARNING THEORY

2.1 Binary classification

A large part of this class will be devoted to one of the simplest problem of statistical learning theory: binary classification (aka pattern recognition [DGL96]). In this problem, we observe $(X_1, Y_1), \ldots, (X_n, Y_n)$ that are *n* independent random copies of $(X, Y) \in \mathcal{X} \times \{0, 1\}$. Denote by $P_{X,Y}$ the joint distribution of (X, Y). The so-called *feature* X lives in some abstract space \mathcal{X} (think \mathbb{R}^d) and $Y \in \{0, 1\}$ is called *label*. For example, X can be a collection of gene expression levels measured on a patient and Y indicates if this person suffers from obesity. The goal of binary classification is to build a rule to predict Y given X using only the data at hand. Such a rule is a function $h : \mathcal{X} \to \{0, 1\}$ called a *classifier*. Some classifiers are better than others and we will favor ones that have low *classification error* $R(h) = \mathbb{P}(h(X) \neq Y)$. Let us make some important remarks.

Fist of all, since $Y \in \{0, 1\}$ then Y has a Bernoulli distribution: so much for distribution free assumptions! However, we will not make assumptions on the marginal distribution of X or, what matters for prediction, the conditional distribution of Y given X. We write, $Y|X \sim \text{Ber}(\eta(X))$, where $\eta(X) = \mathbb{P}(Y = 1|X) = \mathbb{E}[Y|X]$ is called the *regression function* of Y onto X.

Next, note that we did not write $Y = \eta(X)$. Actually we have $Y = \eta(X) + \varepsilon$, where $\varepsilon = Y - \eta(X)$ is a "noise" random variable that satisfies $\mathbb{E}[\varepsilon|X] = 0$. In particular, this noise accounts for the fact that X may not contain enough information to predict Y perfectly. This is clearly the case in our genomic example above: it not whether there is even any information about obesity contained in a patient's genotype. The noise vanishes if and only if $\eta(x) \in \{0, 1\}$ for all $x \in \mathcal{X}$. Figure 2.1 illustrates the case where there is no noise and the the more realistic case where there is noise. When $\eta(x)$ is close to .5, there is essentially no information about Y in X as the Y is determined essentially by a toss up. In this case, it is clear that even with an infinite amount of data to learn from, we cannot predict Y well since there is nothing to learn. We will see what the effect of the noise also appears in the sample complexity.



Figure 2: The thick black curve corresponds to the noiseless case where $Y = \eta(X) \in \{0, 1\}$ and the thin red curve corresponds to the more realistic case where $\eta \in [0, 1]$. In the latter case, even full knowledge of η does not guarantee a perfect prediction of Y.

In the presence of noise, since we cannot predict Y accurately, we cannot drive the classification error R(h) to zero, regardless of what classifier h we use. What is the smallest value that can be achieved? As a thought experiment, assume to begin with that we have all

the information that we may ever hope to get, namely we know the regression function $\eta(\cdot)$. For a given X to classify, if $\eta(X) = 1/2$ we may just toss a coin to decide our prediction and discard X since it contains no information about Y. However, if $\eta(X) \neq 1/2$, we have an edge over random guessing: if $\eta(X) > 1/2$, it means that $\mathbb{P}(Y = 1|X) > \mathbb{P}(Y = 0|X)$ or, in words, that 1 is more likely to be the correct label. We will see that the classifier $h^*(X) = \mathbb{I}(\eta(X) > 1/2)$ (called *Bayes classifier*) is actually the best possible classifier in the sense that

$$R(h^*) = \inf_{h(\cdot)} R(h) \,,$$

where the infimum is taken over all classifiers, i.e. functions from \mathcal{X} to $\{0,1\}$. Note that unless $\eta(x) \in \{0,1\}$ for all $x \in \mathcal{X}$ (noiseless case), we have $R(h^*) \neq 0$. However, we can always look at the *excess risk* $\mathcal{E}(h)$ of a classifier h defined by

$$\mathcal{E}(h) = R(h) - R(h^*) \ge 0.$$

In particular, we can hope to drive the excess risk to zero with enough observations by mimicking h^* accurately.

2.2 Empirical risk

The Bayes classifier h^* , while optimal, presents a major drawback: we cannot compute it because we do not know the regression function η . Instead, we have access to the data $(X_1, Y_1), \ldots, (X_n, Y_n)$, which contains some (but not all) information about η and thus h^* . In order to mimic the properties of h^* recall that it minimizes R(h) over all h. But the function $R(\cdot)$ is unknown since it depends on the unknown distribution $P_{X,Y}$ of (X, Y). We estimate it by the empirical classification error, or simply *empirical risk* $\hat{R}_n(\cdot)$ defined for any classifier h by

$$\hat{R}_n(h) = \frac{1}{n} \sum_{i=1}^n \mathbb{I}(h(X_i) \neq Y_i).$$

Since $\mathbb{E}[\mathbb{I}(h(X_i) \neq Y_i)] = \mathbb{P}(h(X_i) \neq Y_i) = R(h)$, we have $\mathbb{E}[\hat{R}_n(h)] = R(h)$ so $\hat{R}_n(h)$ is an *unbiased* estimator of R(h). Moreover, for any h, by the law of large numbers, we have $\hat{R}_n(h) \to R(h)$ as $n \to \infty$, almost surely. This indicates that if n is large enough, $\hat{R}_n(h)$ should be close to R(h).

As a result, in order to mimic the performance of h^* , let us use the *empirical risk* minimizer (ERM) \hat{h} defined to minimize $\hat{R}_n(h)$ over all classifiers h. This is an easy enough task: define \hat{h} such $\hat{h}(X_i) = Y_i$ for all i = 1, ..., n and h(x) = 0 if $x \notin \{X_1, ..., X_n\}$. We have $\hat{R}_n(\hat{h}) = 0$, which is clearly minimal. The problem with this classifier is obvious: it does not generalize outside the data. Rather, it predicts the label 0 for any x that is not in the data. We could have predicted 1 or any combination of 0 and 1 and still get $\hat{R}_n(\hat{h}) = 0$. In particular it is unlikely that $\mathbb{E}[R(\hat{h})]$ will be small. Important Remark: Recall that $R(h) = \mathbb{P}(h(X) \neq Y)$.

If $\hat{h}(\cdot) = \hat{h}(\{(X_1, Y_1), \dots, (X_n, Y_n)\}; \cdot)$ is constructed from the data, $R(\hat{h})$ denotes the *conditional probability*

$$R(\hat{h}) = \mathbb{P}(\hat{h}(X) \neq Y | (X_1, Y_1), \dots, (X_n, Y_n)).$$

rather than $\mathbb{P}(\hat{h}(X) \neq Y)$. As a result $R(\hat{h})$ is a random variable since it depends on the randomness of the data $(X_1, Y_1), \ldots, (X_n, Y_n)$. One way to view this is to observe that we compute the *deterministic* function $R(\cdot)$ and then plug in the random classifier \hat{h} .

This problem is inherent to any method if we are not willing to make any assumption on the distribution of (X, Y) (again, so much for distribution freeness!). This can actually be formalized in theorems, known as *no-free-lunch* theorems.

Theorem: For any integer $n \ge 1$, any classifier \hat{h} built from $(X_1, Y_1), \ldots, (X_n, Y_n)$ and any $\varepsilon > 0$, there exists a distribution $P_{X,Y}$ for (X, Y) such that $R(h^*) = 0$ and

$$\mathbb{E}R(h_n) \ge 1/2 - \varepsilon$$
.

To be fair, note that here the distribution of the pair (X, Y) is allowed to depend on n which is cheating a bit but there are weaker versions of the no-free-lunch theorem that essentially imply that it is impossible to learn without further assumptions. One such theorem is the following.

Theorem: For any classifier \hat{h} built from $(X_1, Y_1), \ldots, (X_n, Y_n)$ and any sequence $\{a_n\}_n > 0$ that converges to 0, there exists a distribution $P_{X,Y}$ for (X,Y) such that $R(h^*) = 0$ and

 $\mathbb{E}R(\hat{h}_n) \ge a_n$, for all $n \ge 1$

In the above theorem, the distribution of (X, Y) is allowed to depend on the whole sequence $\{a_n\}_n > 0$ but not on a specific n. The above result implies that the convergence to zero of the classification error may be arbitrarily slow.

2.3 Generative vs discriminative approaches

Both theorems above imply that we need to restrict the distribution $P_{X,Y}$ of (X,Y). But isn't that exactly what statistical modeling is? The is answer is not so clear depending on how we perform this restriction. There are essentially two schools: *generative* which is the statistical modeling approach and *discriminative* which is the machine learning approach.

GENERATIVE: This approach consists in restricting the set of candidate distributions $P_{X,Y}$. This is what is done in *discriminant analysis*¹ where it is assumed that the condition dis-

¹Amusingly, the **generative** approach is called **discriminant** analysis but don't let the terminology fool you.

tributions of X given Y (there are only two of them: one for Y = 0 and one for Y = 1) are Gaussians on $\mathcal{X} = \mathbb{R}^d$ (see for example [HTF09] for an overview of this approach).

DISCRIMINATIVE: This is the machine learning approach. Rather than making assumptions directly on the distribution, one makes assumptions on what classifiers are likely to perform correctly. In turn, this allows to eliminate classifiers such as the one described above and that does not generalize well.

While it is important to understand both, we will focus on the discriminative approach in this class. Specifically we are going to assume that we are given a class \mathcal{H} of classifiers such that R(h) is small for some $h \in \mathcal{H}$.

2.4 Estimation vs. approximation

Assume that we are given a class \mathcal{H} in which we expect to find a classifier that performs well. This class may be constructed from domain knowledge or simply computational convenience. We will see some examples in the class. For any candidate classifier \hat{h}_n built from the data, we can decompose its excess risk as follows:

$$\mathcal{E}(\hat{h}_n) = R(\hat{h}_n) - R(h^*) = \underbrace{R(\hat{h}_n) - \inf_{h \in \mathcal{H}} R(h)}_{\text{estimation error}} + \underbrace{\inf_{h \in \mathcal{H}} R(h) - R(h^*)}_{\text{approximation error}}.$$

On the one hand, estimation error accounts for the fact that we only have a finite amount of observations and thus a partial knowledge of the distribution $P_{X,Y}$. Hopefully we can drive this error to zero as $n \to \infty$. But we already know from the no-free-lunch theorem that this will not happen if \mathcal{H} is the set of all classifiers. Therefore, we need to take \mathcal{H} small enough. On the other hand, if \mathcal{H} is too small, it is unlikely that we will find classifier with performance close to that of h^* . A tradeoff between estimation and approximation can be made by letting $\mathcal{H} = \mathcal{H}_n$ grow (but not too fast) with n.

For now, assume that \mathcal{H} is fixed. The goal of statistical learning theory is to understand how the estimation error drops to zero as a function not only of n but also of \mathcal{H} . For the first argument, we will use *concentration inequalities* such as Hoeffding's and Bernstein's inequalities that allow us to control how close the empirical risk is to the classification error by bounding the random variable

$$\left|\frac{1}{n}\sum_{i=1}^{n}\mathbb{I}(h(X_i)\neq Y_i)-\mathbb{I}(h(X)\neq Y)\right|$$

with high probability. More generally we will be interested in results that allow to quantify how close the average of independent and identically distributed (i.i.d) random variables is to their common expected value.

Indeed, since by definition, we have $\hat{R}_n(\hat{h}) \leq \hat{R}_n(h)$ for all $h \in \mathcal{H}$, the estimation error can be controlled as follows. Define $\bar{h} \in \mathcal{H}$ to be any classifier that minimizes $R(\cdot)$ over \mathcal{H} (assuming that such a classifier exist).

$$R(\hat{h}_{n}) - \inf_{h \in \mathcal{H}} R(h) = R(\hat{h}_{n}) - R(\bar{h})$$

= $\underbrace{\hat{R}_{n}(\hat{h}_{n}) - \hat{R}_{n}(\bar{h})}_{\leq 0} + R(\hat{h}_{n}) - \hat{R}_{n}(\hat{h}_{n}) + \hat{R}_{n}(\bar{h}) - R(\bar{h})$
 $\leq |\hat{R}_{n}(\hat{h}_{n}) - R(\hat{h}_{n})| + |\hat{R}_{n}(\bar{h}) - R(\bar{h})|.$

Since \bar{h} is deterministic, we can use a concentration inequality to control $|\hat{R}_n(\bar{h}) - R(\bar{h})|$. However,

$$\hat{R}_n(\hat{h}_n) = \frac{1}{n} \sum_{i=1}^n \mathbb{I}(\hat{h}_n(X_i) \neq Y_i)$$

is **not** the average of independent random variables since \hat{h}_n depends in a complicated manner on all of the pairs $(X_i, Y_i), i = 1, ..., n$. To overcome this limitation, we often use a blunt, but surprisingly accurate tool: we "sup out" \hat{h}_n ,

$$\left|\hat{R}_n(\hat{h}_n) - R(\hat{h}_n)\right| \le \sup_{h \in \mathcal{H}} \left|\hat{R}_n(\hat{h}_n) - R(\hat{h}_n)\right|.$$

Controlling this supremum falls in the scope of suprema of empirical processes that we will study in quite a bit of detail. Clearly the supremum is smaller as \mathcal{H} is smaller but \mathcal{H} should be kept large enough to have good approximation properties. This is the tradeoff between approximation and estimation. It is also know in statistics as the *bias-variance* tradeoff.

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